

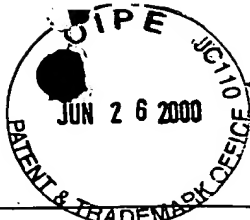
Form PTO-1449 (Substitute)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Attorney Docket Number LAZE-01000US0 SRM	Serial/Patent Number 09/465,592
		Applicant/Patent Owner Culver, et al.	
		Filing/Issue Date December 17, 1999	Group Art Unit 2824 2653

U.S. PATENT DOCUMENTS

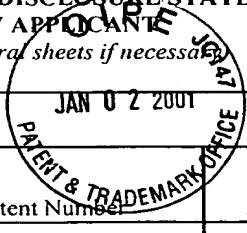
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date
KE	1	4,575,822	3/11/86	Quate	/	/	
KE	2	4,829,507	3/9/89	Kazan et al.	/	/	
KE	3	4,916,688	4/10/90	Foster et al.	/	/	
KE	4	4,945,515	7/31/90	Ooumi et al.	/	/	
KE	5	4,962,480	10/9/90	Ooumi et al.	/	/	
KE	6	4,987,312	1/22/91	Eigler	/	/	
KE	7	5,038,322	8/6/91	Van Loenen	/	/	
KE	8	5,051,977	9/24/91	Goldberg	/	/	
KE	9	5,091,880	2/25/92	Isono et al.	/	/	
KE	10	5,144,148	9/1/92	Eigler	/	/	
KE	11	5,187,367	2/16/93	Miyazaki et al.	/	/	
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KE	13	5,251,200	10/5/93	Hatanaka et al.	/	/	
KE	14	5,262,981	11/16/93	Rabe et al.	/	/	
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KE	16	5,289,455	2/22/94	Kuroda et al.	/	/	
KE	17	5,307,311	4/26/94	Sliwa, Jr.	/	/	
KE	18	5,453,970	9/26/95	Rust et al.	/	/	
KE	19	6,038,916	3/21/00	Cleveland et al.	/	/	

FOREIGN PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation Yes No



OTHER DOCUMENTS (Include Author, Title, Date, Pertinent pages, etc.)		
1c	20	<i>Ion irradiation effects on graphite with the scanning tunneling microscope</i> ; T.C. Shen, et al.; J.Vac.Sci. Technol. B9(2), Mar/Apr 1991; pp.1376-1379
1c	21	<i>Tailoring nanostructures with a scanning tunneling microscope</i> ; U.Stauffer, et al.; J.Vac.Sci. Technol. B9(2), Mar/Apr 1991; pp.1389-1393
1c	22	<i>Gold deposition from a scanning tunneling microscope tip</i> ; H.J. Mamin, et al.; J.Vac.Sci. Technol. B9(2), Mar/Apr 1991; pp.1398-1402
1c	23	<i>Pattern generation on semiconductor surfaces by a scanning tunneling microscope operating in air</i> ; J.A. Dagata, et al.; J.Vac.Sci. Technol. B9(2), Mar/Apr 1991; pp.1384-1388
1c	24	<i>Nanometer-scale hole formation on graphite using a scanning tunneling microscope</i> ; T.R. Albrecht, et al.; Appl.Phys.Lett., Vol.55, No.17, 23 October 1989; pp.1727-1729
1c	25	<i>Has Japan Begun to Move Toward Atomic Level Material Processing?</i> ; M.Aono; Science, Vol. 258; 23 October 1992
Examiner <u>Kim Chen</u> Date Considered <u>9/3/02</u>		
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		
*1 = Copy not submitted because it was submitted in prior application SN <u> </u> / <u> </u> , filed <u> </u> , 19 <u> </u> .		
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Form PTO-1449 (Substitute)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		Attorney Docket Number LAZE-1000US0 SRM		Serial/Patent Number 09/465,592	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use several sheets if necessary)</i>				Applicant/Inventor Owner Joanne P. Culver, et al.			
				Filing/Issue Date December 17, 1999		Group Art Unit 2824 2653	
<div style="display: flex; justify-content: space-between; align-items: center;"> <div style="text-align: center;">  </div> <div>U.S. PATENTS</div> </div>							
Examiner Initial		Patent Number	Issue Date	Inventor	Class	Subclass	Filing Date
lc	1	5,043,578	8/27/1991	Guethner et al.	250	307	
lc	2	5,260,567	11/9/1993	Kuroda et al.	250	359.1	✓
lc	3	5,323,375	6/21/1994	Ihara et al.	369	126	✓
U.S. PATENT PUBLICATIONS							
Examiner Initial		Patent Application Publication Number	Publication Date	Applicant			
PENDING U.S. PATENT APPLICATIONS							
Examiner Initial		Application Number	Filing Date	Inventor	Petition to Expunge? Yes No		
FOREIGN PATENT DOCUMENTS							
Examiner Initial		Document Number	Publication Date	Country	Class	Subclass	Translation Yes No
OTHER DOCUMENTS (Include author (if any), title, publisher and place of publication, date and pertinent pages)							
lc	4	PCT Written Opinion mailed December 18, 2000, International Application No. PCT/US99/30326, filed December 20, 1999					
Examiner	Kim Chin			Date Considered 9/3/02			
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							
*1 = Copy not submitted because it was submitted in prior application SN __/__, filed ____, 20__, relied on under 35 USC §120. *2 = Copy not submitted because it was submitted in prior application SN __/__, filed ____, 20__, relied on under 35 USC §120.							